

S/N 09/834,751

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Sergey A. Velichko et al. Examiner: Craig Steven Miller  
Serial No.: 09/834,751 Group Art Unit: 2857  
Filed: April 13, 2001 Docket: 303.750US1  
Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

MS Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 *et. seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicants respectfully request that this Supplemental Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicants with the next official communication.

Pursuant to 37 C.F.R. §1.97(c)(2), Please charge deposit account 19-0743 in the amount of \$180.00 as set forth in 37 C.F.R. §1.17(p). Please charge any additional fees or credit any overpayment to Deposit Account No. 19-0743.

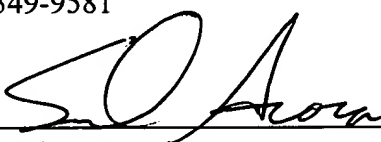
The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.

Respectfully submitted,  
SERGEY A. VELICHKO ET AL.

By their Representatives,  
SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.  
P.O. Box 2938  
Minneapolis, MN 55402  
(612) 349-9581

Date August 12, 2004

By

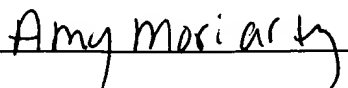


Suneel Arora

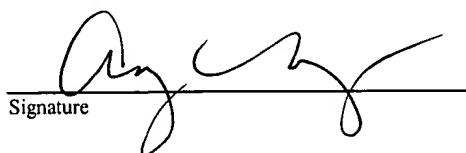
Reg. No. 42,267

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: MS Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 12<sup>th</sup> day of August, 2004.

Name



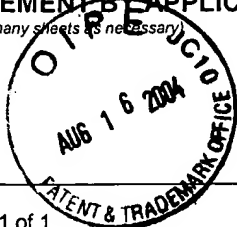
Signature



08/18/2004 HARBELR1 00000129 190743 09834751

01 FC:1806 180.00 DA

Substitute for form 1449A/PTO  
**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**  
(Use as many sheets as necessary)



Complete if Known

Application Number	09/834,751
Filing Date	April 13, 2001
First Named Inventor	Velichko, Sergey
Group Art Unit	2857
Examiner Name	Miller, Craig

Sheet 1 of 1

Attorney Docket No: 303.750US1

### US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	Filing Date If Appropriate
	US-2002/0111775	08/15/2002	Dorough,			04/09/2002
	US-2003/0208340	11/06/2003	Dorough,			05/20/2003
	US-5,360,747	11/01/1994	Larson, S. O., et al.	438	10	06/10/1993
	US-5,806,181	09/15/1998	Khandros, I. Y., et al.	29	874	01/24/1997
	US-6,362,013	03/26/2002	Yoshimura, N.	438	14	04/26/2000
	US-6,370,487	04/09/2004	Dorough,			04/23/1999
	US-6,420,864	07/16/2002	Abraham, M., et al.	324	158.1	04/13/2000
	US-6,466,314	10/15/2002	Lehman, Y.	356	237.1	09/17/1998
	US-6,567,770	05/20/2003	Dorough,			04/09/2002

### FOREIGN PATENT DOCUMENTS

Examiner Initials*	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	T <sup>2</sup>
--------------------	---------------------	------------------	---	-------	----------	----------------

### OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
		DOROUGH, MICHAEL J., et al., "Dynamic Adaptable Semiconductor Testing", <u>IEEE Proceedings of the 2002 International Symposium on Semiconductor Manufacturing, ISSM Catalog, (2002), 1-4</u>	
		SEdgeWICK, R., <u>Algorithms</u> , Second Edition, Addison-Wesley Publishing Company, Inc., (1988), pp. 516-519	

EXAMINER

DATE CONSIDERED